



**MOTOROLA**

# MCM145101

## 256 X 4 BIT STATIC RAM

The MCM145101 family of CMOS RAMs offers ultra low power and fully static operation with a single 5 volt supply. The CMOS 1024-bit devices are organized in 256 words by 4 bits. Separate data inputs and data outputs permit maximum flexibility in bus-oriented systems. Data retention at a power supply as low as 2.0 volts over temperature readily allows design into applications using battery backup for nonvolatility. The MCM145101 is fully static and does not require clocking in standby mode.

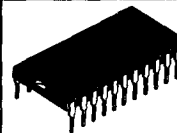
The MCM145101 is fabricated using the Motorola advanced ion-implanted, silicon-gate technology for high performance and high reliability.

- Low Standby Power
- Fast Access Time
- Single + 5.0 Volt Supply
- Fully TTL Compatible—All Inputs and Outputs
- Three-State Output
- Fully Static Operation
- Data Retention to 2.0 Volts
- Direct Replacement for:
  - Intel 5101 Series
  - AMI S5101 Series
  - Hitachi MH435101 Series
- Pin Replacement for Harris HM6501 Series

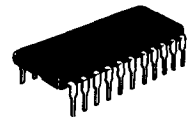
## CMOS LSI

(LOW-POWER COMPLEMENTARY MOS)

## 1024-BIT STATIC RANDOM ACCESS MEMORY

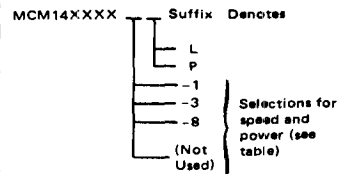


**L SUFFIX**  
CERAMIC PACKAGE  
CASE 736



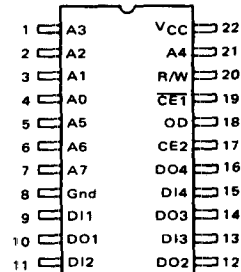
**P SUFFIX**  
PLASTIC PACKAGE  
CASE 708

### ORDERING INFORMATION

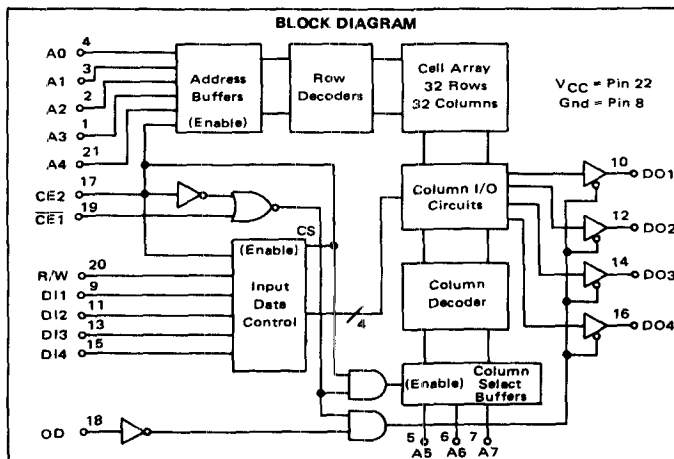


Type Number	Typical Current @ 2 Vdc (μA)	Typical Current @ 5 Vdc (μA)	Max Access (ns)
MCM145101L, MCM145101P	0.14	0.2	650
MCM145101-1L, MCM145101-1P	0.14	0.2	450
MCM145101-3L, MCM145101-3P	0.70	1.0	650
MCM145101-8L, MCM145101-8P	—	10	800

### PIN ASSIGNMENT



### BLOCK DIAGRAM



### TRUTH TABLE

CE1	CE2	OD	R/W	D <sub>In</sub>	Output	Mode
H	X	X	X	X	High Z	Not Selected
X	L	X	X	X	High Z	Not Selected
X	X	H	H	X	High Z	Output Disabled
L	H	H	L	X	High Z	Write
L	H	L	L	X	D <sub>In</sub>	Write
L	H	L	H	X	D <sub>Out</sub>	Read

# MCM145101

## MAXIMUM RATINGS (Voltages referenced to V<sub>SS</sub> Pin 8)

Rating	Symbol	Value	Unit
DC Supply Voltage	V <sub>CC</sub>	-0.5 to +7.0	Vdc
Voltage on Any Pin	V <sub>in</sub>	-0.3 to V <sub>CC</sub> +0.3	Vdc
Operating Temperature Range	T <sub>A</sub>	-40 to +85	°C
Storage Temperature Range	T <sub>stg</sub>	-65 to +150	°C

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance circuit.

## DC OPERATING CONDITIONS AND CHARACTERISTICS (Full operating voltage and temperature range unless otherwise noted)

### DC CHARACTERISTICS (T<sub>A</sub> = 0 to 70°C, V<sub>CC</sub> = 5 V ± 5%)

Characteristic	Symbol	MCM145101-.1			MCM145101-3			MCM145101-8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Input Current	I <sub>in</sub> (2)	-	5.0	-	-	5.0	-	-	5.0	-	nAdc
Input High Voltage	V <sub>IH</sub>	2.2	-	V <sub>CC</sub>	2.2	-	V <sub>CC</sub>	2.2	-	V <sub>CC</sub>	Vdc
Input Low Voltage	V <sub>IL</sub>	-0.3	-	0.65	-0.3	-	0.65	-0.3	-	0.65	Vdc
Output High Voltage (I <sub>OH</sub> = -1.0 mA)	V <sub>OH</sub>	2.4	-	-	2.4	-	-	2.4	-	-	Vdc
Output Low Voltage (I <sub>OL</sub> = 2.0 mA)	V <sub>OL</sub>	-	-	0.4	-	-	0.4	-	-	0.4	Vdc
Output Leakage Current (CE1 = 2.2 V, V <sub>OL</sub> = 0 V to V <sub>CC</sub> )	I <sub>LO</sub> (2)	-	-	±1.0	-	-	±1.0	-	-	±2.0	μAdc
Operating Current (V <sub>in</sub> = V <sub>CC</sub> , except CE1 < 0.65 V, outputs open)	I <sub>CC1</sub>	-	9.0	22	-	9.0	22	-	11	25	mAdc
Operating Current (V <sub>in</sub> = 2.2 V, except CE1 < 0.65 V, outputs open)	I <sub>CC2</sub>	-	13	27	-	13	27	-	15	30	mAdc
Standby Current (CE2 < 0.2 V)	I <sub>CCL</sub> (2),(4)	-	-	10	-	-	200	-	-	500	μAdc

### CAPACITANCE

Characteristic	Symbol	Typ	Max	Unit
Input Capacitance (V <sub>in</sub> = 0 V)	C <sub>in</sub>	4.0	8.0	pF
Output Capacitance (V <sub>out</sub> = 0 V)	C <sub>out</sub>	8.0	12.0	pF

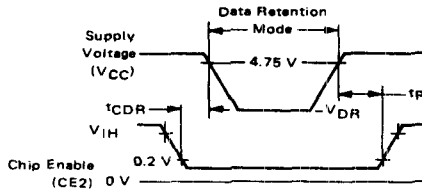
### LOW V<sub>CC</sub> DATA RETENTION CHARACTERISTICS (Excluding MCM145101-8) T<sub>A</sub> = 0°C to 70°C

Parameter	Test Conditions	Symbol	Min	Typ. (1)	Max	Units
V <sub>CC</sub> for Data Retention		V <sub>DR</sub>	2.0	-	-	Vdc
MCM145101 or MCM145101-1 Data Retention Current	CE2 < 0.2 V, V <sub>DR</sub> = 2.0 V,	I <sub>CCDR1</sub>	-	0.14	10	μAdc
MCM145101-3 Data Retention Current	V <sub>DR</sub> = 2.0 V,	I <sub>CCDR2</sub>	-	0.70	200	μAdc
Chip Deselect to Data Retention Time		t <sub>CDR</sub>	0	-	-	ns
Operation Recovery Time		t <sub>R</sub>	t <sub>RC</sub> (3)	-	-	ns

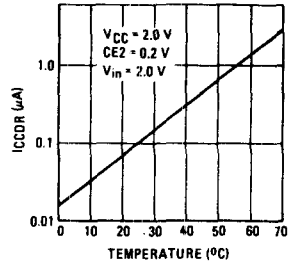
- NOTES:
1. Typical values are T<sub>A</sub> = 25°C and nominal supply voltage.
  2. Current through all inputs and outputs included in I<sub>CCL</sub> measurement.
  3. t<sub>RC</sub> = Read Cycle Time.
  4. Low current state is for CE2 = 0 only.

# MCM145101

**LOW V<sub>CC</sub> DATA RETENTION WAVEFORM**



**TYPICAL I<sub>CCDR</sub> versus TEMPERATURE**



**AC OPERATING CONDITIONS AND CHARACTERISTICS**  
(Full operating voltage and temperature unless otherwise noted)

**AC TEST CONDITIONS**

Condition	Value
Input Pulse Levels	+0.65 V to 2.2 V
Input Rise and Fall Times	20 ns
Output Load —	1 TTL Gate and C <sub>L</sub> = 100 pF
Timing Measurement Reference Level	1.5 Volt

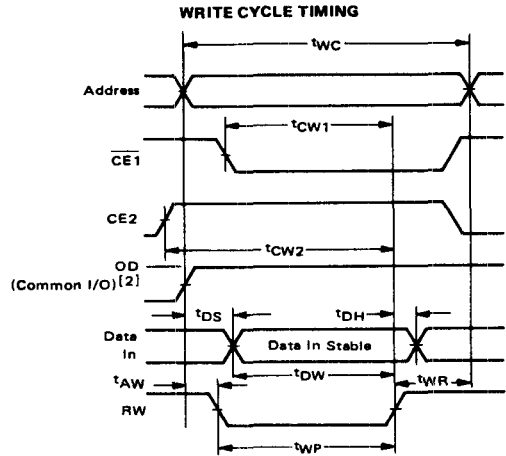
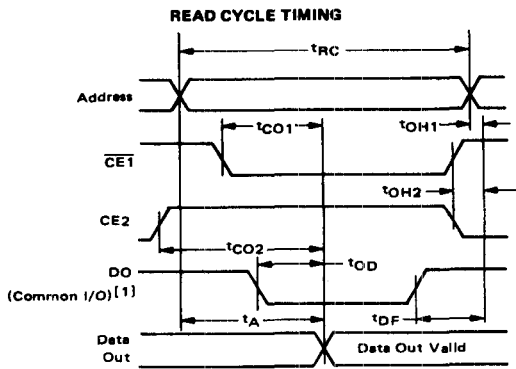
**READ CYCLE**

Parameter	Symbol	MCM145101-1		MCM145101-3		MCM145101-8	
		Min	Max	Min	Max	Min	Max
Read Cycle	t <sub>RC</sub>	450	—	650	—	800	—
Access Time	t <sub>A</sub>	—	450	—	650	—	800
Chip Enable (CE1) to Output	t <sub>CO1</sub>	—	400	—	600	—	800
Chip Enable (CE2) to Output	t <sub>CO2</sub>	—	500	—	700	—	850
Output Disable to Output	t <sub>OD</sub>	—	250	—	350	—	450
Data Output to High Z State	t <sub>DF</sub>	0	130	0	150	0	200
Previous Read Data Valid with Respect to Address Change	t <sub>QH1</sub>	0	—	0	—	0	0
Previous Read Data Valid with Respect to Chip Enable	t <sub>QH2</sub>	0	—	0	—	0	0

**WRITE CYCLE**

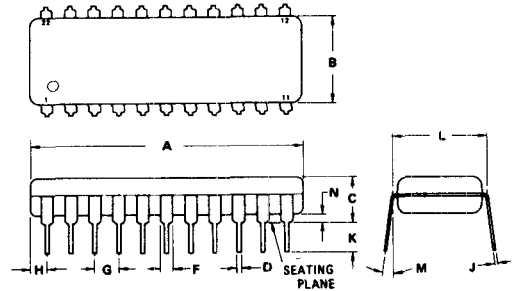
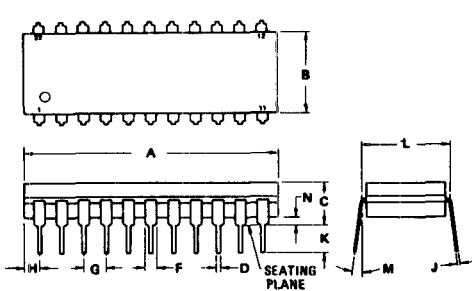
Write Cycle	t <sub>WC</sub>	450	—	650	—	800	—
Write Delay	t <sub>AW</sub>	130	—	150	—	200	—
Chip Enable (CE1) to Write	t <sub>CW1</sub>	350	—	550	—	650	—
Chip Enable (CE2) to Write	t <sub>CW2</sub>	350	—	550	—	650	—
Data Setup	t <sub>DW</sub>	250	—	400	—	450	—
Data Hold	t <sub>DH</sub>	50	—	100	—	100	—
Write Pulse	t <sub>WP</sub>	250	—	400	—	450	—
Write Recovery	t <sub>WR</sub>	50	—	50	—	100	—
Output Disable Setup	t <sub>DS</sub>	130	—	150	—	200	—

# MCM145101



- NOTES: 1. OD may be tied low for separate I/O operation.  
 2. During the write cycle, OD is "high" for common I/O and "don't care" for separate I/O operation.

## PACKAGE DIMENSIONS



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	28.80	27.81	1.095	1.095
B	9.14	8.91	0.360	0.350
C	3.81	5.48	0.150	0.215
D	0.38	0.63	0.015	0.021
F	1.27	1.85	0.050	0.085
G	2.54 BSC		0.100 BSC	
H	0.51	1.27	0.020	0.050
J	0.20	0.30	0.008	0.012
K	2.64	4.32	0.100	0.170
L	8.91	10.41	0.350	0.410
M	18°		18°	
N	0.25	0.89	0.010	0.035

- NOTES:  
 1. LEADS TRUE POSITIONED WITHIN 0.25 mm (0.010) DIA. AT SEATING PLANE AT MAXIMUM MATERIAL CONDITION (DIM "D").  
 2. DIM "L" TO CENTER OF LEADS WHEN FORMED PARALLEL.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	28.83	29.59	1.135	1.165
B	8.64	9.14	0.340	0.360
C	4.57	5.08	0.180	0.200
D	0.36	0.51	0.014	0.020
F	1.02	1.52	0.040	0.060
G	2.41	2.67	0.095	0.105
H	1.78	2.03	0.070	0.080
J	0.20	0.30	0.008	0.012
K	3.05	3.56	0.120	0.140
L	9.65	10.16	0.380	0.400
M	90°		90°	
N	0.51	1.02	0.020	0.040

CERAMIC PACKAGE  
CASE 736-01

PLASTIC PACKAGE  
CASE 708-01